

# EC500

## Design of Secure and Reliable Hardware

Lecture 4

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## Error Models

### Chip-Level Models

Let  $\tilde{y}$  be a  $(T \times n)$  binary output matrix possibly distorted by error.  $T$  is the number of input vectors and  $n$  is the number of primary outputs. Similarly,  $y$  is a  $(T \times n)$  binary matrix of fault free responses and

$$E = \tilde{y} \oplus y \text{ is an error matrix, then } E = \begin{bmatrix} e(1) \\ e(2) \\ \vdots \\ e(T) \end{bmatrix}. y(t), \tilde{y}(t), e(t) \in F_q^n.$$

### Uniform errors

All  $E \neq 0$  are equiprobable

### Correlated errors

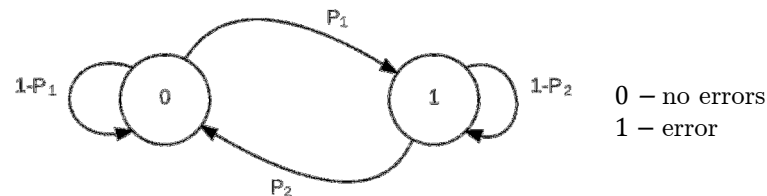
#### Temporal Models

##### a. Time Independent Errors

$e(t), t = 1, 2, \dots, T$  are statistically independent. Most popular model for combinational devices, random test.

##### b. Time Correlated Errors

#### Markov Chain Model



$$P_1 = \text{Prob}(e(t+1) \neq 0 | e(t) = 0)$$

$$P_2 = \text{Prob}(e(t+1) = 0 | e(t) \neq 0)$$

Difficult to compute  $(P_1, P_2)$

##### c. Lazy Errors

A channel is lazy if  $P_2$  is close to 1 (errors are repeating with high probability)

##### d. Burst Errors

A burst error is an error that will distort not more than consecutive bits of length  $b$ .

### Spatial Models

#### Space Independent Errors

Let  $\|e(t)\| = l$

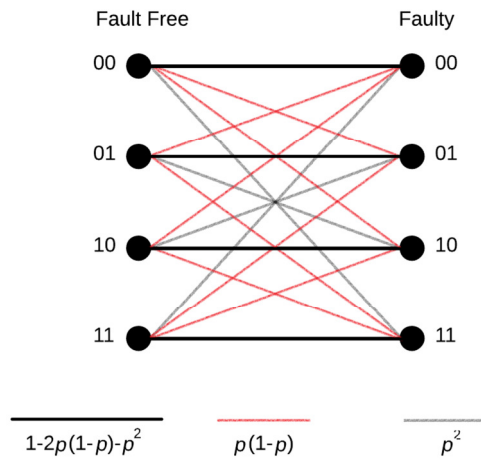
$\|e(t)\| = l$  is the number of ones in  $e(t)$  (Hamming norm of  $e(t)$ ), number of bits at the output distorted at moment  $t$

For any  $l$ :

$\text{Prob}\{\|e(t)\| = l\} = \binom{n}{l} p^l (1-p)^{n-l}$ , where  $p$  is the bit distortion rate and  $\text{Prob}(0 \rightarrow 1) = \text{Prob}(0 \rightarrow 1)$  distortions.

This model is efficient for networks with limited fanouts.

*Example:* Independent Errors ( $n = 2$ )



*Space Symmetrical Models*

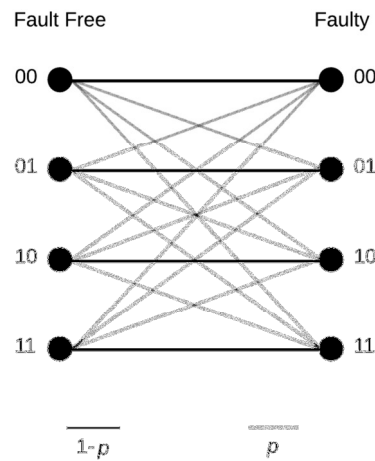
a. For any  $t$ :

All  $e(t) \neq 0$  are equiprobable.

$$Prob\{e(t) = i\} = \begin{cases} 1 - (2^n - 1)p, & i = 00 \dots 0 \\ p, & i \neq 00 \dots 0 \end{cases}$$

Space symmetrical model is very popular. This model is efficient for networks with large fanouts.

*Example:* Symmetrical Errors ( $n = 2$ )



**b. Space Errors of a Given Magnitude**

For any  $t$ :

$$Prob\{e(t) = i\} = \begin{cases} 1 - p, & i = 0 \dots 0 \\ p, & i = a \\ 0, & \text{otherwise} \end{cases} \quad \text{for some } n\text{-bit vector } a$$

This model is efficient for networks where every fault affects only a fixed set of outputs for all input vectors.

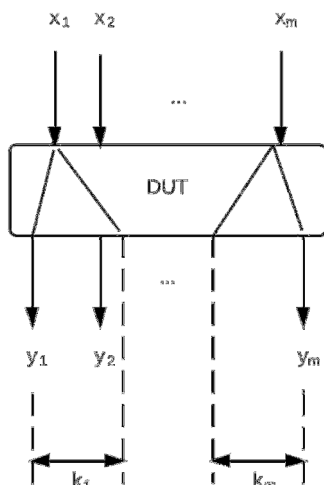
**General Spatial Model**

$\{P_0, P_1, \dots, P_{2^{n-1}}\}$  – error distribution in space  
 $P_0 = Prob\{e(t) = 0\}$  – no errors  
 $P_1 = Prob\{e(t) = i\}$

Space error distribution is difficult to compute. It depends on a DUT and the input for the DUT.

**Computation of Space Error Distributions**

Let  $k_i$  outputs depend on  $x_i$  for the DUT.



$k_i$  is the size of dependence cone for input  $x_i, (i = 1, 2, \dots, m)$

Then, the number of different error patterns  $N_e$  due to single stuck-at faults is upperbounded by  $N_e \leq \sum_{i=1}^m (2^{k_i} - 1)$

Example:

$m = 32, n = 32, \max_i k_i = 10$   
 $N_e \leq 32 \times (2^{10} - 1) \ll 2^{32}$

**Improvement for the Upperbound on  $N_e$**

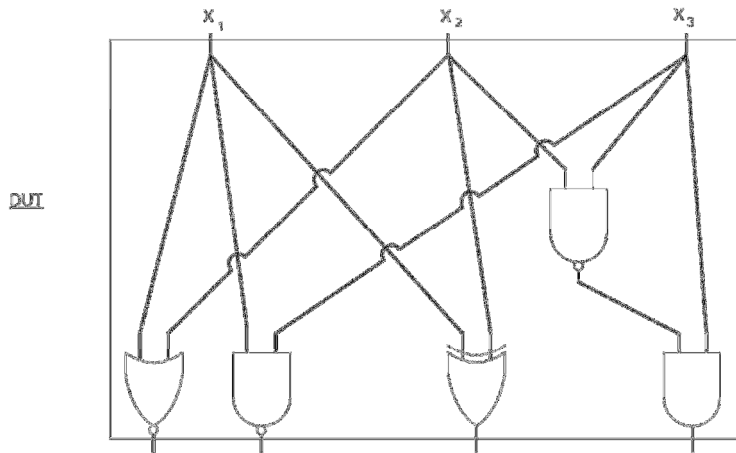
Let  $Y_i$  be the set of outputs that depend on input  $x_i, (i = 1, 2, \dots, m)$

Let  $|Y_i| = k_i, |Y_i \cap Y_j| = k_{ij}, |Y_i \cap Y_j \cap Y_r| = k_{ijr}, \dots$

Then,  $N_e \leq \sum_i (2^{k_i} - 1) - \sum_{i,j} (2^{k_{ij}} - 1) + \sum_{i,j,r} (2^{k_{ijr}} - 1) - \dots$

Time independent, space symmetrical models are the most popular models.

Example: Single Stuck-at Faults



$$N_e \leq (2^3 - 1) + (2^3 - 1) + (2^2 - 1)$$

$$k_1 = 3, k_2 = 3, k_3 = 2$$

$$k_{12} = 2, k_{13} = 1, k_{23} = 1, k_{123} = 0$$

$$N_e \leq \sum_i (2^{k_i} - 1) - \sum_{i,j} (2^{k_{ij}} - 1) + \sum_{i,j,r} (2^{k_{ijr}} - 1) - \dots$$

For the previous example,

$$N_e \leq [(2^3 - 1) + (2^3 - 1) + (2^2 - 1)] - [(2^2 - 1) + (2^1 - 1) + (2^1 - 1)] + (2^0 - 1) = 12$$

### Board or System Level Error Models

#### Independent Errors

Probability of  $l$  component being faulty is  $\binom{S}{l} p^l (1-p)^{S-l}$ , where

$S$  – is the size of a board or system

$p$  – probability of an error at the output of a component

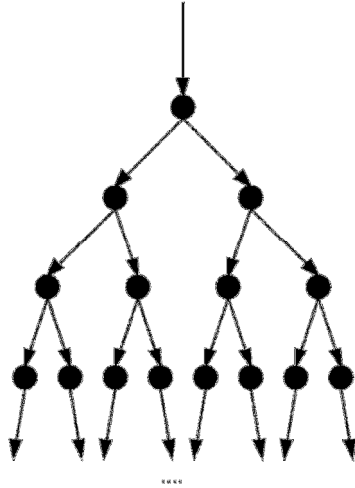
( $p$  can be computed by using one of the chip level error models)

### Conclusion on Chip Level Error Models

Space independent model predicts maximum probability of missing an error (pessimistic estimation) and space symmetrical model predicts minimum probability of missing (optimistic estimation). Symmetrical model predicts in large networks more precisely than other models.

**System Correlated Errors**  
 Equiprobable single node failures.

Example: Tree Processor



Possible error patterns are:

- 10000000
- 01000000
- 00100000
- 00010000
- 00001000
- 00000100
- 00000010
- 00000001
- 11000000
- 00110000
- 00001100
- 00000011
- 11110000
- 00001111
- 11111111

In this table, 1 indicates that output of the corresponding processor is distorted.

All errors due to a fault in a single node or in a single link are equiprobable.

Errors in  $y_i$  are distributed according to one of the chip error models!